

DATA SHEET

74HC00; 74HCT00 Quad 2-input NAND gate

Product specification
Supersedes data of 1997 Aug 26

2003 Jun 30

Quad 2-input NAND gate

74HC00; 74HCT00

FEATURES

- Complies with JEDEC standard no. 8-1A
- ESD protection:
HBM EIA/JESD22-A114-A exceeds 2000 V
MM EIA/JESD22-A115-A exceeds 200 V
- Specified from -40 to $+85$ °C and -40 to $+125$ °C.

DESCRIPTION

The 74HC00/74HCT00 are high-speed Si-gate CMOS devices and are pin compatible with low power Schottky TTL (LSTTL). They are specified in compliance with JEDEC standard no. 7A.

The 74HC00/74HCT00 provide the 2-input NAND function.

QUICK REFERENCE DATA

GND = 0 V; $T_{amb} = 25$ °C; $t_r = t_f = 6$ ns.

| SYMBOL | PARAMETER | CONDITIONS | TYPICAL | | UNIT |
|-------------------|--|-------------------------------|---------|---------|------|
| | | | 74HC00 | 74HCT00 | |
| t_{PHL}/t_{PLH} | propagation delay nA, nB to nY | $C_L = 15$ pF; $V_{CC} = 5$ V | 7 | 10 | ns |
| C_I | input capacitance | | 3.5 | 3.5 | pF |
| C_{PD} | power dissipation capacitance per gate | notes 1 and 2 | 22 | 22 | pF |

Notes

- C_{PD} is used to determine the dynamic power dissipation (P_D in μ W).

$$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o) \text{ where:}$$

f_i = input frequency in MHz;

f_o = output frequency in MHz;

C_L = output load capacitance in pF;

V_{CC} = supply voltage in Volts;

N = total load switching outputs;

$\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs.

- For 74HC00 the condition is $V_I = \text{GND}$ to V_{CC} .

For 74HCT00 the condition is $V_I = \text{GND}$ to $V_{CC} - 1.5$ V.

FUNCTION TABLE

See note 1.

| INPUT | | OUTPUT |
|-------|----|--------|
| nA | nB | nY |
| L | L | H |
| L | H | H |
| H | L | H |
| H | H | L |

Note

- H = HIGH voltage level;
L = LOW voltage level.

Quad 2-input NAND gate

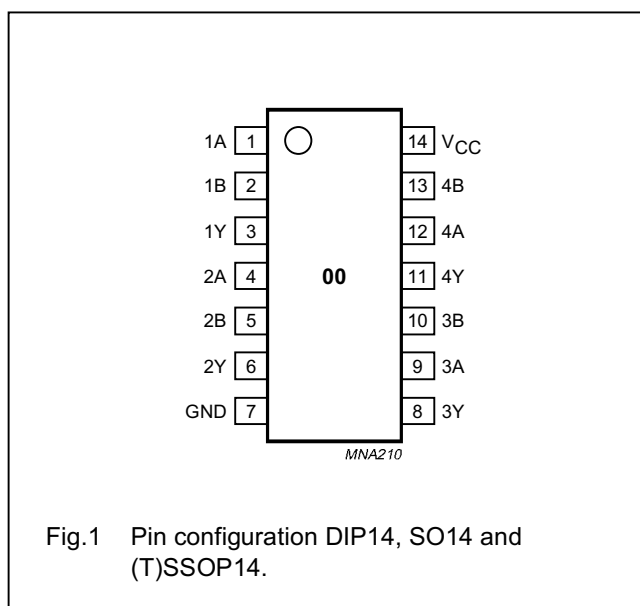
74HC00; 74HCT00

ORDERING INFORMATION

| TYPE NUMBER | PACKAGE | | | | |
|-------------|-------------------|------|----------|----------|----------|
| | TEMPERATURE RANGE | PINS | PACKAGE | MATERIAL | CODE |
| 74HC00N | -40 to +125 °C | 14 | DIP14 | plastic | SOT27-1 |
| 74HCT00N | -40 to +125 °C | 14 | DIP14 | plastic | SOT27-1 |
| 74HC00D | -40 to +125 °C | 14 | SO14 | plastic | SOT108-1 |
| 74HCT00D | -40 to +125 °C | 14 | SO14 | plastic | SOT108-1 |
| 74HC00DB | -40 to +125 °C | 14 | SSOP14 | plastic | SOT337-1 |
| 74HCT00DB | -40 to +125 °C | 14 | SSOP14 | plastic | SOT337-1 |
| 74HC00PW | -40 to +125 °C | 14 | TSSOP14 | plastic | SOT402-1 |
| 74HCT00PW | -40 to +125 °C | 14 | TSSOP14 | plastic | SOT402-1 |
| 74HC00BQ | -40 to +125 °C | 14 | DHVQFN14 | plastic | SOT762-1 |
| 74HCT00BQ | -40 to +125 °C | 14 | DHVQFN14 | plastic | SOT762-1 |

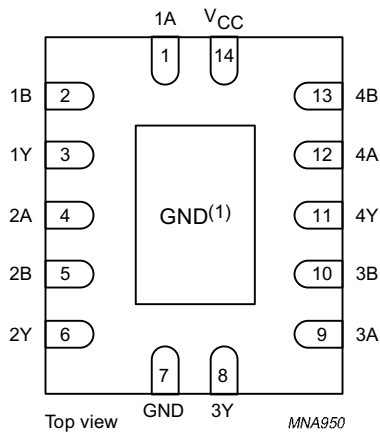
PINNING

| PIN | SYMBOL | DESCRIPTION |
|-----|-----------------|----------------|
| 1 | 1A | data input |
| 2 | 1B | data input |
| 3 | 1Y | data output |
| 4 | 2A | data input |
| 5 | 2B | data input |
| 6 | 2Y | data output |
| 7 | GND | ground (0 V) |
| 8 | 3Y | data output |
| 9 | 3A | data input |
| 10 | 3B | data input |
| 11 | 4Y | data output |
| 12 | 4A | data input |
| 13 | 4B | data input |
| 14 | V _{CC} | supply voltage |



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(1) The die substrate is attached to this pad using conductive die attach material. It can not be used as a supply pin or input.

Fig.2 Pin configuration DHVQFN14.

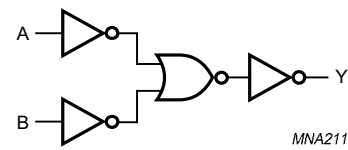


Fig.3 Logic diagram (one gate).

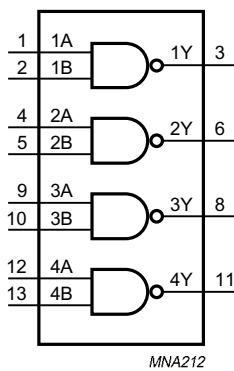


Fig.4 Function diagram.

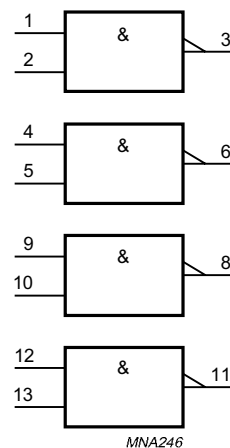


Fig.5 IEC logic symbol.

Quad 2-input NAND gate

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RECOMMENDED OPERATING CONDITIONS

| SYMBOL | PARAMETER | CONDITIONS | 74HC00 | | | 74HCT00 | | | UNIT |
|------------|-------------------------------|--|--------|------|----------|---------|------|----------|------|
| | | | MIN. | TYP. | MAX. | MIN. | TYP. | MAX. | |
| V_{CC} | supply voltage | | 2.0 | 5.0 | 6.0 | 4.5 | 5.0 | 5.5 | V |
| V_I | input voltage | | 0 | – | V_{CC} | 0 | – | V_{CC} | V |
| V_O | output voltage | | 0 | – | V_{CC} | 0 | – | V_{CC} | V |
| T_{amb} | operating ambient temperature | see DC and AC characteristics per device | –40 | +25 | +125 | –40 | +25 | +125 | °C |
| t_r, t_f | input rise and fall times | $V_{CC} = 2.0\text{ V}$ | – | – | 1000 | – | – | – | ns |
| | | $V_{CC} = 4.5\text{ V}$ | – | 6.0 | 500 | – | 6.0 | 500 | ns |
| | | $V_{CC} = 6.0\text{ V}$ | – | – | 400 | – | – | – | ns |

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).

| SYMBOL | PARAMETER | CONDITIONS | MIN. | MAX. | UNIT |
|-------------------|-------------------------------|--|------|------|------|
| V_{CC} | supply voltage | | –0.5 | +7.0 | V |
| I_{IK} | input diode current | $V_I < -0.5\text{ V}$ or $V_I > V_{CC} + 0.5\text{ V}$ | – | ±20 | mA |
| I_{OK} | output diode current | $V_O < -0.5\text{ V}$ or $V_O > V_{CC} + 0.5\text{ V}$ | – | ±20 | mA |
| I_O | output source or sink current | $-0.5\text{ V} < V_O < V_{CC} + 0.5\text{ V}$ | – | ±25 | mA |
| I_{CC}, I_{GND} | V_{CC} or GND current | | – | ±50 | mA |
| T_{stg} | storage temperature | | –65 | +150 | °C |
| P_{tot} | power dissipation | $T_{amb} = -40\text{ to }+125\text{ °C}$; note 1 | – | 500 | mW |

Note

- For DIP14 packages: above 70 °C derate linearly with 12 mW/K.
For SO14 packages: above 70 °C derate linearly with 8 mW/K.
For SSOP14 and TSSOP14 packages: above 60 °C derate linearly with 5.5 mW/K.
For DHVQFN14 packages: above 60 °C derate linearly with 4.5 mW/K.

Quad 2-input NAND gate

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DC CHARACTERISTICS

Type 74HC00

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

| SYMBOL | PARAMETER | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
|--|----------------------------|--|---------------------|------|------|------|------|
| | | OTHER | V _{CC} (V) | | | | |
| T _{amb} = -40 to +85 °C; note 1 | | | | | | | |
| V _{IH} | HIGH-level input voltage | | 2.0 | 1.5 | 1.2 | – | V |
| | | | 4.5 | 3.15 | 2.4 | – | V |
| | | | 6.0 | 4.2 | 3.2 | – | V |
| V _{IL} | LOW-level input voltage | | 2.0 | – | 0.8 | 0.5 | V |
| | | | 4.5 | – | 2.1 | 1.35 | V |
| | | | 6.0 | – | 2.8 | 1.8 | V |
| V _{OH} | HIGH-level output voltage | V _I = V _{IH} or V _{IL} I _O = -20 µA | 2.0 | 1.9 | 2.0 | – | V |
| | | I _O = -20 µA | 4.5 | 4.4 | 4.5 | – | V |
| | | I _O = -20 µA | 6.0 | 5.9 | 6.0 | – | V |
| | | I _O = -4.0 mA | 4.5 | 3.84 | 4.32 | – | V |
| | | I _O = -5.2 mA | 6.0 | 5.34 | 5.81 | – | V |
| V _{OL} | LOW-level output voltage | V _I = V _{IH} or V _{IL} I _O = 20 µA | 2.0 | – | 0 | 0.1 | V |
| | | I _O = 20 µA | 4.5 | – | 0 | 0.1 | V |
| | | I _O = 20 µA | 6.0 | – | 0 | 0.1 | V |
| | | I _O = 4.0 mA | 4.5 | – | 0.15 | 0.33 | V |
| | | I _O = 5.2 mA | 6.0 | – | 0.16 | 0.33 | V |
| I _{LI} | input leakage current | V _I = V _{CC} or GND | 6.0 | – | – | ±1.0 | µA |
| I _{OZ} | 3-state output OFF current | V _I = V _{IH} or V _{IL} ; V _O = V _{CC} or GND | 6.0 | – | – | ±5.0 | µA |
| I _{CC} | quiescent supply current | V _I = V _{CC} or GND; I _O = 0 | 6.0 | – | – | 20 | µA |

Quad 2-input NAND gate

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| SYMBOL | PARAMETER | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
|---|----------------------------|--|---------------------|------|------|-------|------|
| | | OTHER | V _{CC} (V) | | | | |
| T_{amb} = -40 to +125 °C | | | | | | | |
| V _{IH} | HIGH-level input voltage | | 2.0 | 1.5 | – | – | V |
| | | | 4.5 | 3.15 | – | – | V |
| | | | 6.0 | 4.2 | – | – | V |
| V _{IL} | LOW-level input voltage | | 2.0 | – | – | 0.5 | V |
| | | | 4.5 | – | – | 1.35 | V |
| | | | 6.0 | – | – | 1.8 | V |
| V _{OH} | HIGH-level output voltage | V _I = V _{IH} or V _{IL} I _O = -20 µA | 2.0 | 1.9 | – | – | V |
| | | I _O = -20 µA | 4.5 | 4.4 | – | – | V |
| | | I _O = -20 µA | 6.0 | 5.9 | – | – | V |
| | | I _O = -4.0 mA | 4.5 | 3.7 | – | – | V |
| | | I _O = -5.2 mA | 6.0 | 5.2 | – | – | V |
| V _{OL} | LOW-level output voltage | V _I = V _{IH} or V _{IL} I _O = 20 µA | 2.0 | – | – | 0.1 | V |
| | | I _O = 20 µA | 4.5 | – | – | 0.1 | V |
| | | I _O = 20 µA | 6.0 | – | – | 0.1 | V |
| | | I _O = 4.0 mA | 4.5 | – | – | 0.4 | V |
| | | I _O = 5.2 mA | 6.0 | – | – | 0.4 | V |
| I _{LI} | input leakage current | V _I = V _{CC} or GND | 6.0 | – | – | ±1.0 | µA |
| I _{OZ} | 3-state output OFF current | V _I = V _{IH} or V _{IL} ; V _O = V _{CC} or GND | 6.0 | – | – | ±10.0 | µA |
| I _{CC} | quiescent supply current | V _I = V _{CC} or GND; I _O = 0 | 6.0 | – | – | 40 | µA |

Note

1. All typical values are measured at T_{amb} = 25 °C.

Quad 2-input NAND gate

74HC00; 74HCT00

Type 74HCT00

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

| SYMBOL | PARAMETER | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
|--|-------------------------------------|---|---------------------|------|------|------|------|
| | | OTHER | V _{CC} (V) | | | | |
| T_{amb} = -40 to +85 °C; note 1 | | | | | | | |
| V _{IH} | HIGH-level input voltage | | 4.5 to 5.5 | 2.0 | 1.6 | – | V |
| V _{IL} | LOW-level input voltage | | 4.5 to 5.5 | – | 1.2 | 0.8 | V |
| V _{OH} | HIGH-level output voltage | V _I = V _{IH} or V _{IL} I _O = -20 µA | 4.5 | 4.4 | 4.5 | – | V |
| | | I _O = -4.0 mA | 4.5 | 3.84 | 4.32 | – | V |
| V _{OL} | LOW-level output voltage | V _I = V _{IH} or V _{IL} I _O = 20 µA | 4.5 | – | 0 | 0.1 | V |
| | | I _O = 4.0 mA | 4.5 | – | 0.15 | 0.33 | V |
| I _{LI} | input leakage current | V _I = V _{CC} or GND | 5.5 | – | – | ±1.0 | µA |
| I _{oz} | 3-state output OFF current | V _I = V _{IH} or V _{IL} ; V _O = V _{CC} or GND; I _O = 0 | 5.5 | – | – | ±5.0 | µA |
| I _{CC} | quiescent supply current | V _I = V _{CC} or GND; I _O = 0 | 5.5 | – | – | 20 | µA |
| ΔI _{CC} | additional supply current per input | V _I = V _{CC} - 2.1 V; I _O = 0 | 4.5 to 5.5 | – | 150 | 675 | µA |
| T_{amb} = -40 to +125 °C | | | | | | | |
| V _{IH} | HIGH-level input voltage | | 4.5 to 5.5 | 2.0 | – | – | V |
| V _{IL} | LOW-level input voltage | | 4.5 to 5.5 | – | – | 0.8 | V |
| V _{OH} | HIGH-level output voltage | V _I = V _{IH} or V _{IL} I _O = -20 µA | 4.5 | 4.4 | – | – | V |
| | | I _O = -4.0 mA | 4.5 | 3.7 | – | – | V |
| V _{OL} | LOW-level output voltage | V _I = V _{IH} or V _{IL} I _O = 20 µA | 4.5 | – | – | 0.1 | V |
| | | I _O = 4.0 mA | 4.5 | – | – | 0.4 | V |
| I _{LI} | input leakage current | V _I = V _{CC} or GND | 5.5 | – | – | ±1.0 | µA |
| I _{oz} | 3-state output OFF current | V _I = V _{IH} or V _{IL} ; V _O = V _{CC} or GND; I _O = 0 | 5.5 | – | – | ±10 | µA |
| I _{CC} | quiescent supply current | V _I = V _{CC} or GND; I _O = 0 | 5.5 | – | – | 40 | µA |
| ΔI _{CC} | additional supply current per input | V _I = V _{CC} - 2.1 V; I _O = 0 | 4.5 to 5.5 | – | – | 735 | µA |

Note1. All typical values are measured at T_{amb} = 25 °C.

Quad 2-input NAND gate

74HC00; 74HCT00

AC CHARACTERISTICS

Type 74HC00

GND = 0 V; $t_r = t_f = 6$ ns; $C_L = 50$ pF.

| SYMBOL | PARAMETER | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
|--|--------------------------------|-----------------|---------------------|------|------|------|------|
| | | WAVEFORMS | V _{CC} (V) | | | | |
| T_{amb} = -40 to +85 °C; note 1 | | | | | | | |
| t _{PHL} /t _{PLH} | propagation delay nA, nB to nY | see Fig.6 | 2.0 | – | 25 | 115 | ns |
| | | see Fig.6 | 4.5 | – | 9 | 23 | ns |
| | | see Fig.6 | 6.0 | – | 7 | 20 | ns |
| t _{THL} /t _{TLH} | output transition time | | 2.0 | – | 19 | 95 | ns |
| | | | 4.5 | – | 7 | 19 | ns |
| | | | 6.0 | – | 6 | 16 | ns |
| T_{amb} = -40 to +125 °C | | | | | | | |
| t _{PHL} /t _{PLH} | propagation delay nA, nB to nY | see Fig.6 | 2.0 | – | – | 135 | ns |
| | | see Fig.6 | 4.5 | – | – | 27 | ns |
| | | see Fig.6 | 6.0 | – | – | 23 | ns |
| t _{THL} /t _{TLH} | output transition time | | 2.0 | – | – | 110 | ns |
| | | | 4.5 | – | – | 22 | ns |
| | | | 6.0 | – | – | 19 | ns |

Note

1. All typical values are measured at T_{amb} = 25 °C.

Type 74HCT00

GND = 0 V; $t_r = t_f = 6$ ns; $C_L = 50$ pF

| SYMBOL | PARAMETER | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
|--|--------------------------------|-----------------|---------------------|------|------|------|------|
| | | WAVEFORMS | V _{CC} (V) | | | | |
| T_{amb} = -40 to +85 °C; note 1 | | | | | | | |
| t _{PHL} /t _{PLH} | propagation delay nA, nB to nY | see Fig.6 | 4.5 | – | 12 | 24 | ns |
| t _{THL} /t _{TLH} | output transition time | | 4.5 | – | – | 29 | ns |
| T_{amb} = -40 to +125 °C | | | | | | | |
| t _{PHL} /t _{PLH} | propagation delay nA, nB to nY | see Fig.6 | 4.5 | – | – | 29 | ns |
| t _{THL} /t _{TLH} | output transition time | | 4.5 | – | – | 22 | ns |

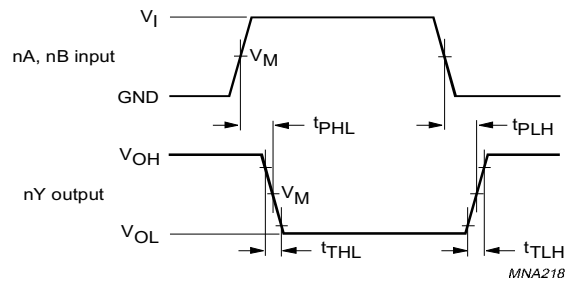
Note

1. All typical values are measured at T_{amb} = 25 °C.

Quad 2-input NAND gate

74HC00; 74HCT00

AC WAVEFORMS



74HC00: $V_M = 50\%$; $V_I = \text{GND to } V_{CC}$.
74HCT00: $V_M = 1.3 \text{ V}$; $V_I = \text{GND to } 3 \text{ V}$.

Fig.6 Waveforms showing the input (nA, nB) to output (nY) propagation delays.

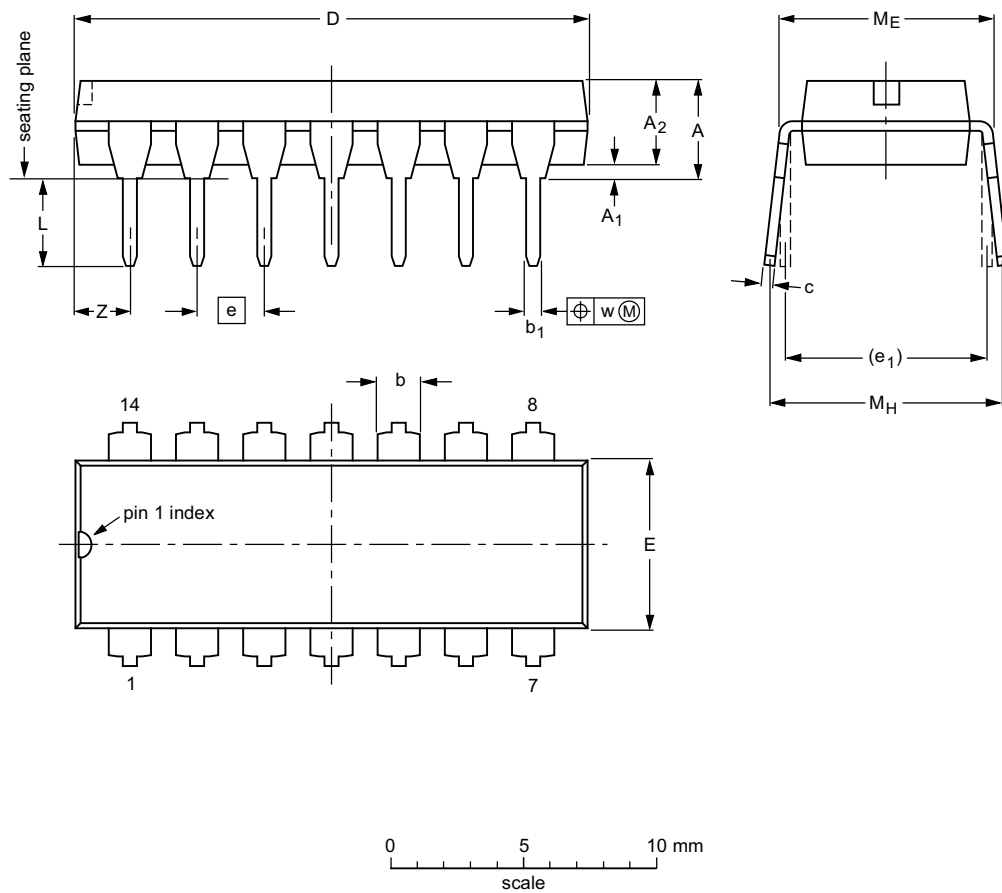
Quad 2-input NAND gate

74HC00; 74HCT00

PACKAGE OUTLINES

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

| UNIT | A max. | A ₁ min. | A ₂ max. | b | b ₁ | c | D ⁽¹⁾ | E ⁽¹⁾ | e | e ₁ | L | M _E | M _H | w | z ⁽¹⁾ max. |
|--------|--------|---------------------|---------------------|----------------|----------------|----------------|------------------|------------------|------|----------------|--------------|----------------|----------------|-------|-----------------------|
| mm | 4.2 | 0.51 | 3.2 | 1.73 1.13 | 0.53 0.38 | 0.36 0.23 | 19.50 18.55 | 6.48 6.20 | 2.54 | 7.62 | 3.60 3.05 | 8.25 7.80 | 10.0 8.3 | 0.254 | 2.2 |
| inches | 0.17 | 0.02 | 0.13 | 0.068 0.044 | 0.021 0.015 | 0.014 0.009 | 0.77 0.73 | 0.26 0.24 | 0.1 | 0.3 | 0.14 0.12 | 0.32 0.31 | 0.39 0.33 | 0.01 | 0.087 |

Note

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

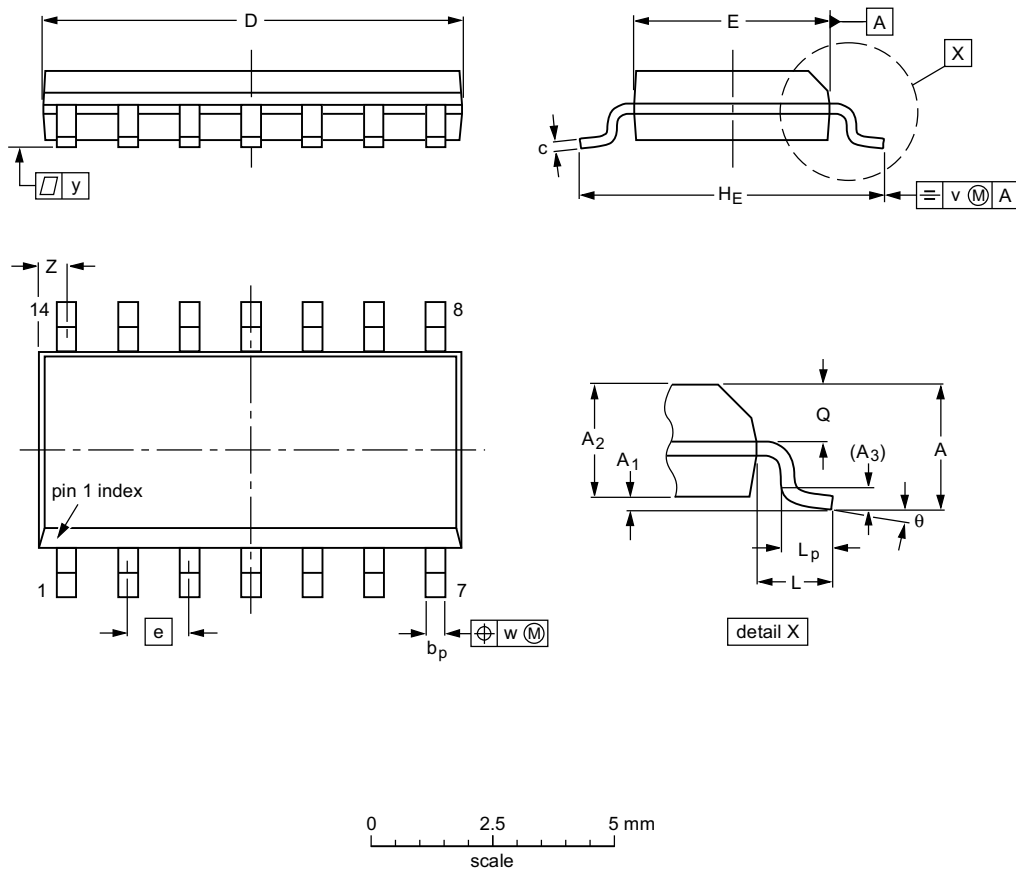
| OUTLINE VERSION | REFERENCES | | | EUROPEAN PROJECTION | ISSUE DATE |
|-----------------|------------|--------|-----------|---------------------|----------------------|
| | IEC | JEDEC | JEITA | | |
| SOT27-1 | 050G04 | MO-001 | SC-501-14 | | 99-12-27 03-02-13 |

Quad 2-input NAND gate

74HC00; 74HCT00

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

| UNIT | A max. | A ₁ | A ₂ | A ₃ | b _p | c | D ⁽¹⁾ | E ⁽¹⁾ | e | H _E | L | L _p | Q | v | w | y | z ⁽¹⁾ | θ |
|--------|--------|----------------|----------------|----------------|----------------|------------------|------------------|------------------|------|----------------|-------|----------------|----------------|------|------|-------|------------------|----------|
| mm | 1.75 | 0.25 0.10 | 1.45 1.25 | 0.25 | 0.49 0.36 | 0.25 0.19 | 8.75 8.55 | 4.0 3.8 | 1.27 | 6.2 5.8 | 1.05 | 1.0 0.4 | 0.7 0.6 | 0.25 | 0.25 | 0.1 | 0.7 0.3 | 8° 0° |
| inches | 0.069 | 0.010 0.004 | 0.057 0.049 | 0.01 | 0.019 0.014 | 0.0100 0.0075 | 0.35 0.34 | 0.16 0.15 | 0.05 | 0.244 0.228 | 0.041 | 0.039 0.016 | 0.028 0.024 | 0.01 | 0.01 | 0.004 | 0.028 0.012 | |

Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

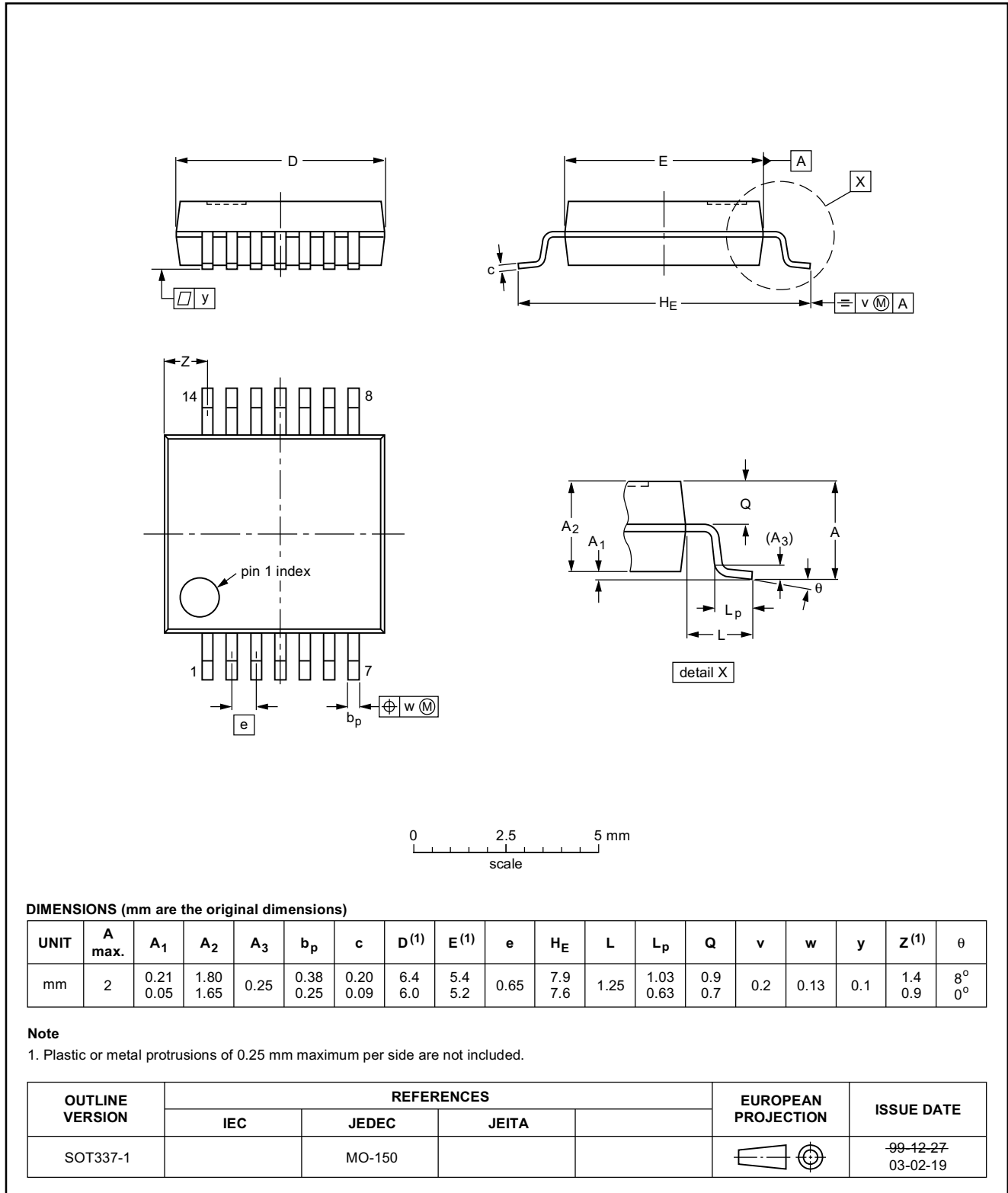
| OUTLINE VERSION | REFERENCES | | | | EUROPEAN PROJECTION | ISSUE DATE |
|-----------------|------------|--------|-------|--|---------------------|----------------------|
| | IEC | JEDEC | JEITA | | | |
| SOT108-1 | 076E06 | MS-012 | | | | 99-12-27 03-02-19 |

Quad 2-input NAND gate

74HC00; 74HCT00

SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

SOT337-1

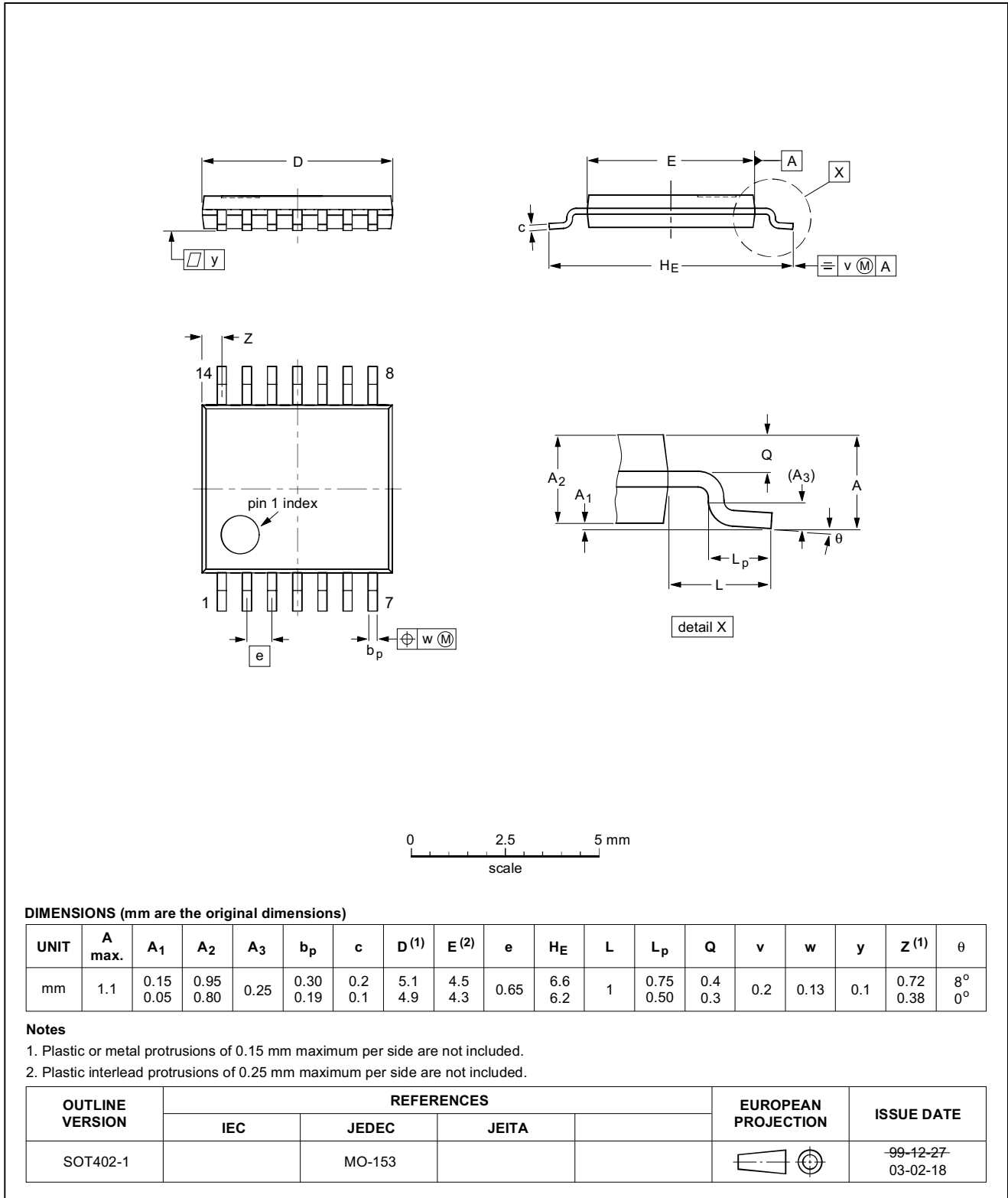


Quad 2-input NAND gate

74HC00; 74HCT00

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1

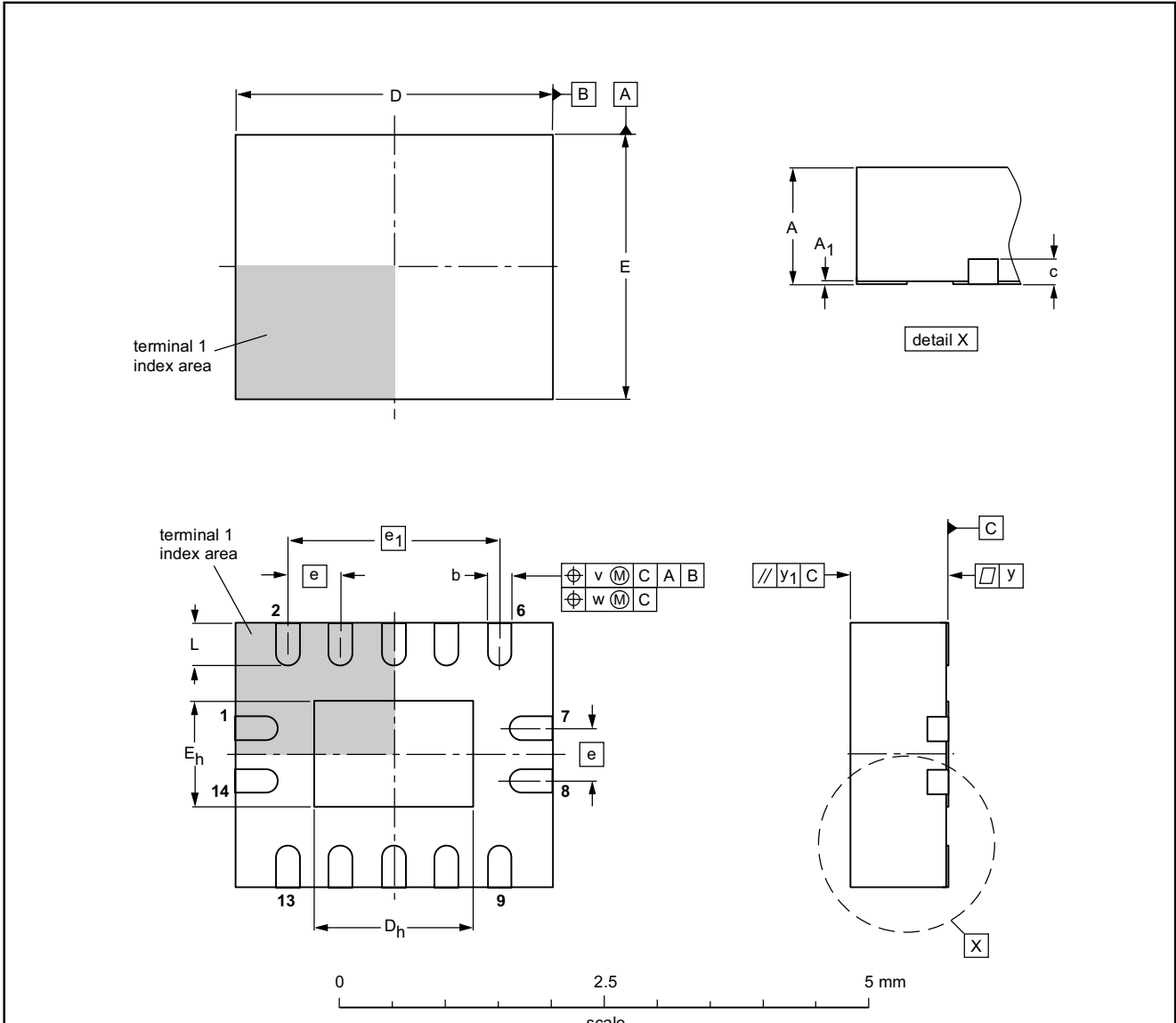


Quad 2-input NAND gate

74HC00; 74HCT00

DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 x 3 x 0.85 mm

SOT762-1



DIMENSIONS (mm are the original dimensions)

| UNIT | A ⁽¹⁾ max. | A ₁ | b | c | D ⁽¹⁾ | D _h | E ⁽¹⁾ | E _h | e | e ₁ | L | v | w | y | y ₁ |
|------|--------------------------|----------------|--------------|-----|------------------|----------------|------------------|----------------|-----|----------------|------------|-----|------|------|----------------|
| mm | 1 | 0.05 0.00 | 0.30 0.18 | 0.2 | 3.1 2.9 | 1.65 1.35 | 2.6 2.4 | 1.15 0.85 | 0.5 | 2 | 0.5 0.3 | 0.1 | 0.05 | 0.05 | 0.1 |

Note

1. Plastic or metal protrusions of 0.075 mm maximum per side are not included.

| OUTLINE VERSION | REFERENCES | | | | EUROPEAN PROJECTION | ISSUE DATE |
|-----------------|------------|--------|-------|--|---------------------|----------------------|
| | IEC | JEDEC | JEITA | | | |
| SOT762-1 | --- | MO-241 | --- | | | 02-10-17 03-01-27 |

Quad 2-input NAND gate

74HC00; 74HCT00

DATA SHEET STATUS

| LEVEL | DATA SHEET STATUS ⁽¹⁾ | PRODUCT STATUS ⁽²⁾⁽³⁾ | DEFINITION |
|-------|----------------------------------|----------------------------------|--|
| I | Objective data | Development | This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice. |
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For sales offices addresses send e-mail to: sales.addresses@www.semiconductors.philips.com.

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